

Resource Summary Report

Generated by RRID on Aug 6, 2026

FEI: Meridian M System for Semiconductors

RRID:SCR_019897

Type: Tool

Proper Citation

FEI: Meridian M System for Semiconductors (RRID:SCR_019897)

Resource Information

URL: <https://www.fei.com/products/efa/meridian-m-for-semiconductors/>

Proper Citation: FEI: Meridian M System for Semiconductors (RRID:SCR_019897)

Description: Electrical failure analysis system for semiconductors that uses high sensitivity broadband DBX photon emission and Static Laser Stimulation techniques to pinpoint the location of electrical faults.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Meridian M System for Semiconductors

Resource ID: SCR_019897

Alternate IDs: Model_Number_Meridian_M

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190635+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Meridian M System for Semiconductors.

No alerts have been found for FEI: Meridian M System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.